

## **secondary ionization**

*in mass spectrometry*

The process in which ions are ejected from a sample surface (which may be a solid or substrate dissolved in a solvent matrix) as a result of bombardment by a primary beam of atoms or ions.

**Source:**

PAC, 1991, 63, 1541 (*Recommendations for nomenclature and symbolism for mass spectroscopy (including an appendix of terms used in vacuum technology). (Recommendations 1991)*) on page 1548